

PATENTIN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Bruce et al.	Examiner:	Chan, E.
Serial No.:	09/915,883	Group Art Unit:	2829
Filed:	July 26, 2001	Docket No.:	AMDA.508PA
Title:	INTEGRATED CIRCUIT DEFECT ANALYSIS USING LIQUID CRYSTAL		

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being transmitted via facsimile only-Formal Entry, to the attention of Examiner Chan. Mail Stop Non-Fee Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on July 9, 2003.

10 Pages Total

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By:

Kelly W. Higgins  
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OFFICE ACTION RESPONSE**FAX RECEIVED**

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TECHNOLOGY CENTER 2800

Mail Stop Non-Fee Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In response to the non-final Office Action dated April 16, 2003, please consider the following remarks.